Hybrid 8j338 Traveler

May 10, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J338 has die: 165-068 165-075 165-076 165-083 161-129 161-133 161-137 161-140

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j338 classification info. Created 11:01:50 05/10/00

Hybrid 8j338 quality: fair
Chip classification: good good good good fair good fair fair
Bad channels (chip-channel): 4-123 7-35
Bad cells: none
Random bad capacitors (chip-cell-channel): 6-44-18 6-7-46 7-24-61
   7-27-61 7-28-88 7-28-89 7-29-61 7-31-61 7-40-60 7-40-61 7-41-61
   7-7-61
Channels at pedestal needed for DCMS: 30.7 31.6 33.6 33.6 32.3 29.7 29.6 28.5
```

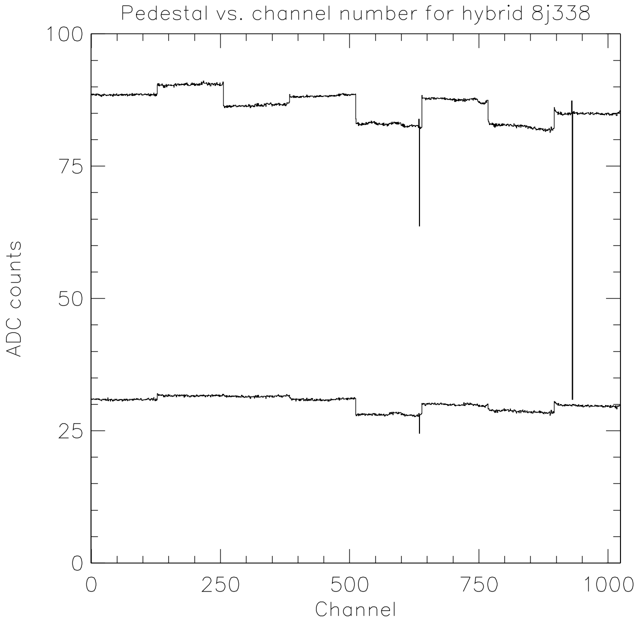
4 Comments

HV tested.

5 Pedestal

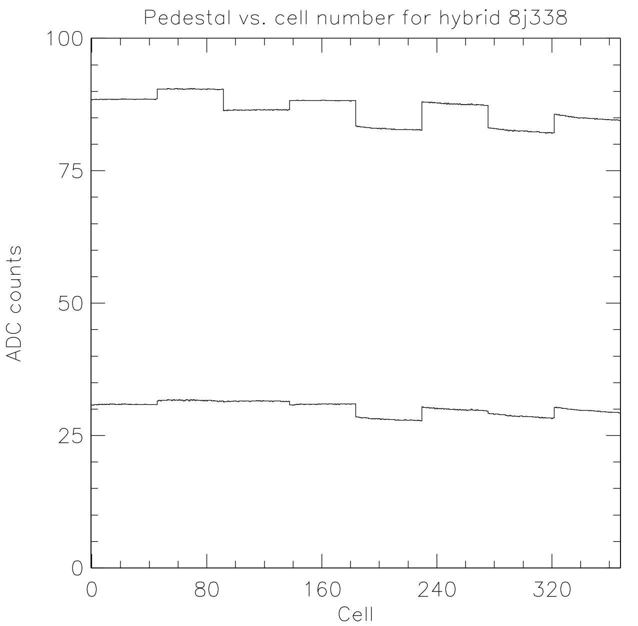
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

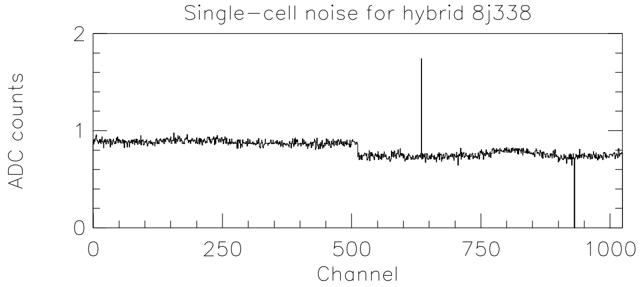
Pedestal vs. Pipeline Cell ID

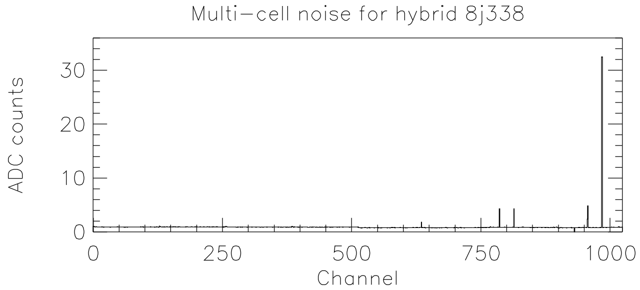


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

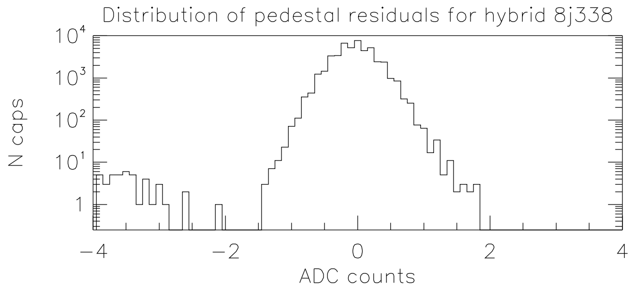
RMS Noise

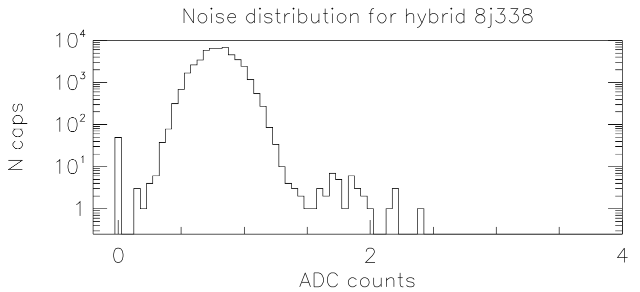




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in